Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((mask same (layout same design)) and (performance adj variation) and (((crititcal adj dimension) adj variation) same (edge adj (placement adj error)) same tolerance) and features)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:33
L2	0	((mask same (layout same design)) and (performance adj variation) and (((critical adj dimension) adj variation) same (edge adj (placement adj error)) same tolerance) and features)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:34
L3	1	((mask same (layout same design)) and (performance adj variation) and (((critical adj dimension) same variation) same (edge adj (placement adj error)) same tolerance) and features)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:35
L4	1	(((mask same (layout same design)) and (performance adj variation) and (((critical adj dimension) same variation) same (edge adj (placement adj error)) same tolerance) and features)). CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:37
L5	0	((mask same (layout same design)) and (performance adj variation) and (((critical adj dimension) same variation) same (overlay adj error) same tolerance) and features)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:37
L6	1	(((mask and (layout and design)) and (performance and variation) and (((critical and dimension) same variation) and (edge and (placement and error)) and tolerance) and features)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:38
S1	781	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:00
S2	1089	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:41

S3	0	(716/21).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correctiom same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:55
S4	0	(716/19).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correctiom same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:53
S5	0	("716"/$).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correctiom same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:53
S6	0	(mask same (design adj layout)) and (yield) and (minimum same correctiom same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:53
S7	0	(mask same (design same layout)) and (yield) and (minimum same correctiom same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:55
S8	38	(mask same (design same layout)) and (yield) and (correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:00
S9	0	(716/21).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:56
S10	1	(716/19).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:56
S11	1	("716"/$).ccls. and (mask same (design adj layout)) and (yield) and (minimum same correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:57
S12	2	(mask same (design adj layout)) and (yield) and (minimum same correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 16:57

S13	3	(mask same (design same layout)) and (yield) and (minimum same correction same cost)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:01
S14	0	(mask same (design same layout)) and (yield) and (minimum adj (correction adj cost))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:01
S15	2	(mask same (design same layout)) and (yield) and (minimum same (correction adj cost))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:30
S16	1	(mask same (design same layout)) and (yield) and (minimum same (correction adj cost)) and (probability adj (density adj function)) and (correction adj algorithm) and (signal adj (arrival adj time))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:13
S17	1	((mask same (design same layout)) and (yield) and (minimum same (correction adj cost)) and (probability adj (density adj function)) and (correction adj algorithm) and (signal adj (arrival adj time))).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:12
S18	0	(mask same (design same layout)) and (torleab$6 or accept$7) and (performance adj variation) and ((critical adj dimension) adj variation) and (edge adj (placement adj error))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:25
S19	0	(mask same (design same layout)) and (tolerab$6 or accept$7) and (performance adj variation) and ((critical adj dimension) adj variation) and (edge adj (placement adj error))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:27
S20	1	(mask same (design same layout)) and (tolerable or acceptable) and (performance adj variation) and ((critical adj dimension) same variation) and tolerance and (edge adj (placement adj error))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:28
S21	1	(mask same (design same layout)) and (yield) and (minimum same (correction same cost)) and mapping and (resolution adj enhancement)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/26 17:32

S22	1	((mask same (layout same delay)) same (correction or modification)) and (cost and yield)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:03
S23	21077	(((mask same (layout same delay)) same (correction or modification) sam algorithm) and (cost and yield))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:04
S24	1	(((mask same (layout same delay)) same (correction or modification) same algorithm) and (cost and yield))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:04
S25	0	(((mask same (layout same delay)) same (correction or modification) same algorithm) and (cost and yield)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:05
S26	4	(((mask same (layout same design)) same (correction or modification) same algorithm) and (cost and yield))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:08
S27	1	(((mask same (layout same design)) same (correction or modification) same algorithm) and (cost and yield)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:17
S28	1	(((mask same (layout same design)) same (probability adj (density adj function)) same (arrival adj time)) and (algorithm) and (cost and yield))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:19
S29	1	(((mask same (layout same design)) same (probability adj (density adj function)) same (arrival adj time)) and (algorithm) and (cost and yield)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:23
S30	1	(((mask and (layout and design)) and (probability and (density and function)) and (arrival and time)) and (algorithm) and (cost and yield)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/27 11:22

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